

**Search Notes**

Application/Control No.

10/003,557

Examiner

Nhon T. Diep

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2621

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Fast Search	7/7/07	N.D.